Notice of References Cited Application/Control No. 10/840,108 Examiner SAKET K. DAFTUAR Applicant(s)/Patent Under Reexamination WEEL, MARTIN Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,456,234	09-2002	Johnson, William J.	342/357.09
*	В	US-6,195,657	02-2001	Rucker et al.	707/5
*	С	US-2005/0187976	08-2005	Goodman et al.	707/104.1
*	D	US-2005/0267944	12-2005	Little, Charles Reeves II	709/207
*	Е	US-2006/0020662	01-2006	Robinson, Gary	709/203
*	F	US-2008/0016205	01-2008	Svendsen, Hugh	709/224
*	G	US-2002/0007418	01-2002	Hegde et al.	709/231
*	Η	US-2003/0217102	11-2003	Jystad et al.	709/203
*	I	US-2004/0055014	03-2004	Edelson, Justin	725/110
*	J	US-2005/0071881	03-2005	Deshpande, Sachin G.	725/088
*	К	US-2005/0240494	10-2005	Cue et al.	705/027
*	L	US-2006/0294212	12-2006	Kikkawa et al.	709/223
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
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	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.